

IN THE SPECIFICATION:

Please amend the specification as follows:

Please substitute the paragraph beginning at page 12, line 10, with the following.

-- In the fourth step, values obtained by measuring the overlay marks are substituted into column vectors on the ~~right~~ left side in equations 1 to 14 to be described later, and the equations are solved. At this time, a vernier scale mark position error within the shot transferred by the first layer that corresponds to a distortion (which will be described later) can be obtained. In addition, the position error of each shot transferred by the first layer, the position error of each shot transferred by the second layer, and the relative position error of $m_2 \times n_2$ main scale marks transferred by the second layer can be obtained. --